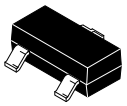
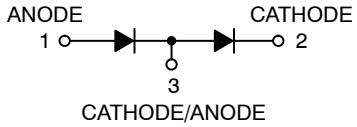
NUP1301

Low Capacitance Diode Array for ESD Protection in a Single Data Line

NUP1301 is a MicroIntegration device designed to provide protection for sensitive components from possible harmful electrical transients; for example, ESD (electrostatic discharge).



SOT−23
CASE 318
STYLE 11



Features

- Low Capacitance (0.9 pF Maximum)
- Single Package Integration Design
- Provides ESD Protection for JEDEC Standards JESD22
  - Machine Model = Class C
  - Human Body Model = Class 3B
- Protection for IEC61000−4−2 (Level 4)
  - 8.0 kV (Contact)
  - 15 kV (Air)
- Ensures Data Line Speed and Integrity
- Fewer Components and Less Board Space
- Direct the Transient to Either Positive Side or to the Ground
- SZ Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC−Q101 Qualified and PPAP Capable
- Pb−Free Package is Available

Applications

- T1/E1 Secondary IC Protection
- T3/E3 Secondary IC Protection
- HDSL, IDSL Secondary IC Protection
- Video Line Protection
- Microcontroller Input Protection
- Base Stations
- I^2C Bus Protection

MAXIMUM RATINGS (Each Diode) (T_J = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Reverse Voltage	V_R	70	Vdc
Forward Current	I_F	215	mAdc
Peak Forward Surge Current	$I_{FM(surge)}$	500	mAdc
Repetitive Peak Reverse Voltage	V_{RRM}	70	V
Average Rectified Forward Current (Note 1) (averaged over any 20 ms period)	$I_{F(AV)}$	715	mA
Repetitive Peak Forward Current	I_{FRM}	450	mA
Non−Repetitive Peak Forward Current t = 1.0 μs t = 1.0 ms t = 1.0 S	I_{FSM}	 2.0 1.0 0.5	A

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. FR−5 = 1.0 × 0.75 × 0.062 in.

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance Junction−to−Ambient	$R_{\theta JA}$	625	°C/W
Lead Solder Temperature Maximum 10 Seconds Duration	T_L	260	°C
Junction Temperature	T_J	−65 to 150	°C
Storage Temperature	T_{stg}	−65 to +150	°C

ELECTRICAL CHARACTERISTICS (T_J = 25°C unless otherwise noted) (Each Diode)

Characteristic	Symbol	Min	Typ	Max	Unit
OFF CHARACTERISTICS					
Reverse Breakdown Voltage ($I_{(BR)}$ = 100 μA)	$V_{(BR)}$	70	–	–	Vdc
Reverse Voltage Leakage Current (V_R = 70 Vdc) (V_R = 25 Vdc, T_J = 150°C) (V_R = 70 Vdc, T_J = 150°C)	I_R	 – – –	 – – –	 2.5 30 50	μAdc
Diode Capacitance (between I/O and ground) (V_R = 0, f = 1.0 MHz)	C_D	–	–	0.9	pF
Forward Voltage (I_F = 1.0 mAdc) (I_F = 10 mAdc) (I_F = 50 mAdc) (I_F = 150 mAdc)	V_F	 – – – –	 – – – –	 715 855 1000 1250	mV_{dc}

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

2. FR−5 = 1.0 × 0.75 × 0.062 in.
3. Alumina = 0.4 × 0.3 × 0.024 in, 99.5% alumina.
4. Include SZ-prefix devices where applicable.

Figure 1. ESD Test Circuit

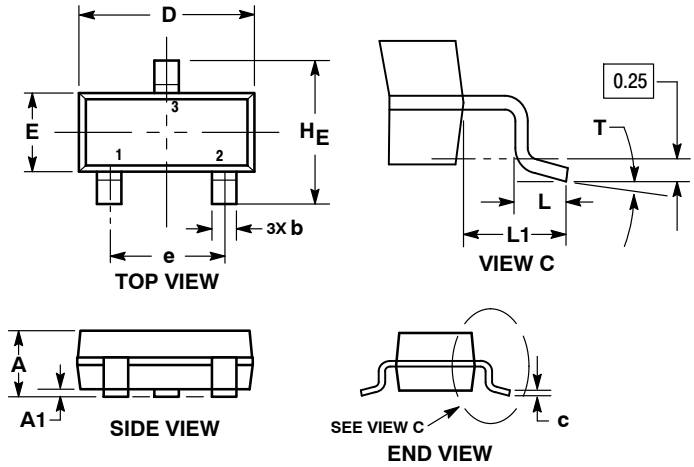
APPLICATION NOTE

Electrostatic Discharge

A common means of protecting high−speed data lines is to employ low−capacitance diode arrays in a rail−to−rail configuration. Two devices per line are connected between two fixed voltage references such as V_{CC} and ground. When the transient voltage exceeds the forward voltage (V_F) drop of the diode plus the reference voltage, the diodes direct the surge to the supply rail or ground. This method has several advantages including low loading capacitance, fast response time, and inherent bidirectionality (within the reference voltages). See Figure 1 for the test circuit used to verify the ESD rating for this device.

PACKAGE DIMENSIONS

SOT−23 (TO−236)
CASE 318−08
ISSUE AR

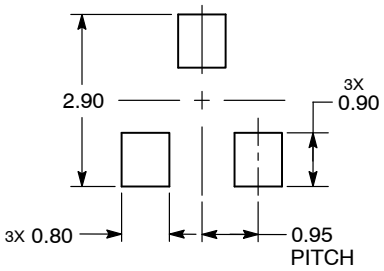


NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
2. CONTROLLING DIMENSION: MILLIMETERS.
3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH. MINIMUM LEAD THICKNESS IS THE MINIMUM THICKNESS OF THE BASE MATERIAL.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.

	MILLIMETERS			INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX
A	0.89	1.00	1.11	0.035	0.039	0.044
A1	0.01	0.06	0.10	0.000	0.002	0.004
b	0.37	0.44	0.50	0.015	0.017	0.020
c	0.08	0.14	0.20	0.003	0.006	0.008
D	2.80	2.90	3.04	0.110	0.114	0.120
E	1.20	1.30	1.40	0.047	0.051	0.055
e	1.78	1.90	2.04	0.070	0.075	0.080
L	0.30	0.43	0.55	0.012	0.017	0.022
L1	0.35	0.54	0.69	0.014	0.021	0.027
H_E	2.10	2.40	2.64	0.083	0.094	0.104
T	0°	−−−	10 °	0 °	−−−	10 °

STYLE 11:
PIN 1. ANODE
2. CATHODE
3. CATHODE−ANODE

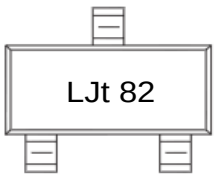
RECOMMENDED SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

*For additional information on our Pb−Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

Marking



ORDERING INFORMATION

Order code	Package	Base qty	Delivery mode
UMW NUP1301	SOT-23	3000	Tape and reel